

FX604

N-Channel Silicon MOSFET

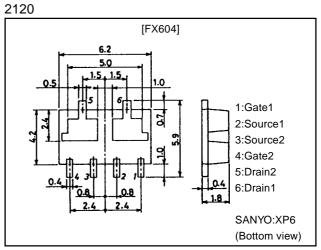
Ultrahigh-Speed Switching Applications

Features

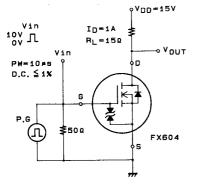
- Composite type composed of two low ON-resistance N-channel MOSFET chips for ultrahigh-speed switching and low-voltage drive.
- · Facilitates high-density mounting.
- The FX604 is formed with two chips, each being equivalent to the 2SK1467, placed in one package.
- \cdot Matched pair characteristics.

Package Dimensions

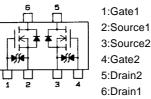
unit:mm



Switching Time Test Clrcuit



Electrical Connection



(Top view)

Specifications

Absolute Maximum Ratings at Ta = 25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	V _{DSS}		30	V
Gate-to-Source Voltage	VGSS		±15	V
Drain Current (DC)	۱ _D		2	A
Drain Current (Pulse)	I _{DP}	PW≤10µs, duty cycle≤1%	8	A
Allowable Power Dissipation	PD	Tc=25°C, 1unit	6	W
	PD	Mounted on ceramic board (750mm ² ×0.8mm) 1unit	1.5	W
Total Dissipation	Ρ _T	Mounted on ceramic board (750mm ² ×0.8mm)	2	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

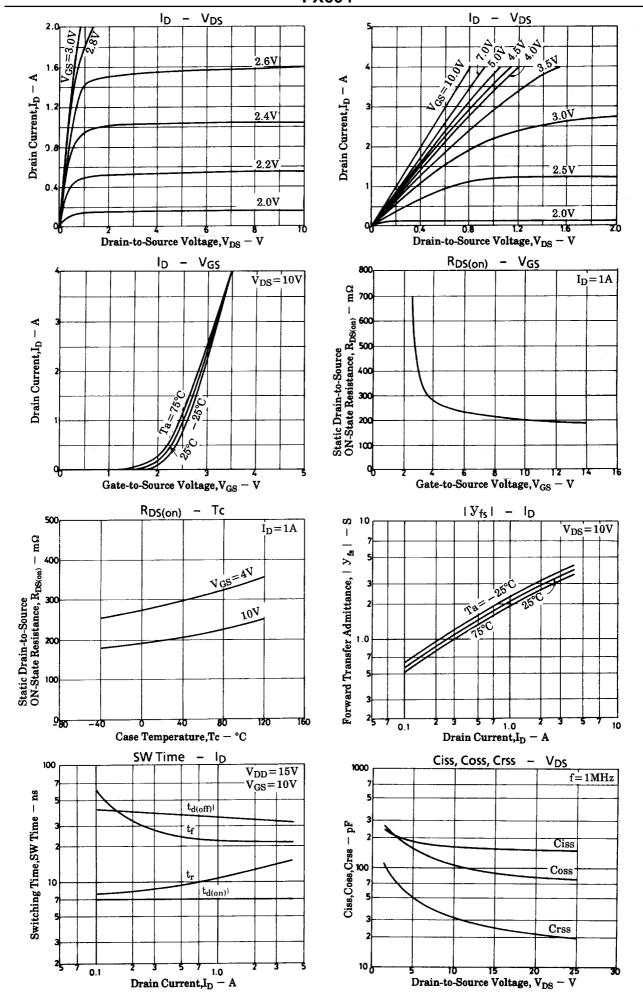
· Marking:604

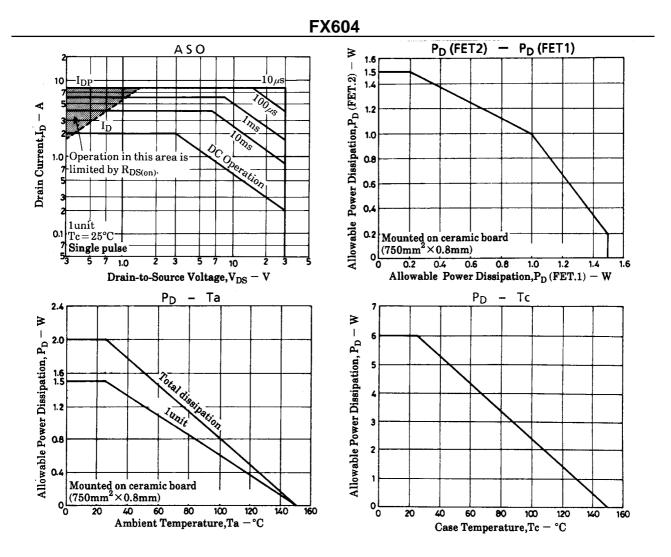
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Electrical Characteristics at Ta = 25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Unit
D-S Breakdown Voltage	V(BR)DSS	I _D =1mA, V _{GS} =0	20			V
Zero-Gate Voltage Drain Current	IDSS	V _{DS} =30V, V _{GS} =0			100	μΑ
Gate-to-Source Leakage Current	IGSS	V _{GS} =±12, V _{DS} =0			±10	μΑ
Cutoff Voltage	V _{GS(off)}	V _{DS} =10V, I _D =1mA	1.0		2.0	V
Forward Transfer Admittance	Y _{fs}	V _{DS} =10V, I _D =1mA	1.2	2.0		S
Static Drain-to-Source ON-State Resistance	R _{DS(on)}	I _D =1A, V _{GS} =10V		0.18	0.25	Ω
	R _{DS(on)}	I _D =1A, V _{GS} =4V		0.25	0.38	Ω
Input Capacitance	Ciss	V _{DS} =10V, f=1MHz		170		pF
Output Capacitance	Coss	V _{DS} =10V, f=1MHz		100		pF
Reverse Transfer Capacitance	Crss	V _{DS} =10V, f=1MHz		30		pF
Turn-ON Delay Time	td(on)	See Specified Test Circuit		7		ns
Rise Time	tr	See Specified Test Circuit		11		ns
Turn-OFF Delay Time	td(off)	See Specified Test Circuit		35		ns
Fall Time	t _f	See Specified Test Circuit		25		ns
Diode Forward Voltage	V _{SD}	I _S =2A, V _{GS} =0		1.0		V





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